Guest Editor:

Dr. David Bigaud
LARIS laboratory on complex systems engineering, University of Angers, Angers, France
david.bigaud@univ-angers.fr

Deadline for manuscript submissions: closed (15 May 2021)

Message from the Guest Editor

The O&M phase of buildings covers more than 50 years of their total life span and represents between 70% and 80% of their life cycle costs. Achieving smart building management with the objectives of ensuring continuity of services and activities, extending their service life and maintaining user satisfaction, is a complex issue in O&M and requires addressing many key topics, ranging from availability of O&M data to optimization of maintenance planning, and including diagnosis methods.

In this Special Issue, we expect papers about O&M data: What are the key indicators to follow? How do we ensure data integrity? Studies can be proposed on measurements of O&M data, on the optimal placement of sensors, on data fusion, and on use of emergent sensors. We are also particularly interested in papers giving proof of value about the use of digital twins for building O&M.

Keywords:

- operation and maintenance
- monitoring
- sensors
- diagnosis
- data analytics
- prognosis
- optimization

Dr. David Bigaud
Guest Editor
Editor-in-Chief

Prof. Dr. Takayoshi Kobayashi
Advanced Ultrafast Laser Research Center, The University of Electro-Communications, 1-5-1, Chofugaoka, Chofu, Tokyo 182-8585, Japan

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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Applied Sciences
MDPI, St. Alban-Anlage 66
4052 Basel, Switzerland
Tel: +41 61 683 77 34
Fax: +41 61 302 89 18
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